Application/Control No. 10/039,627 Examiner Hae M Hyeon Applicant(s)/Patent Under Reexamination HAMM ET AL. Art Unit Page 1 of 1

Notic of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,900,303	02-1990	Lemelson, Jerome H.	604/514
	В	US-5,010,886	04-1991	Passafaro et al.	600/439
	С	US-5,026,367	06-1991	Leckrone et al.	606/7
	D	US-5,039,193	08-1991	Snow et al.	385/25
	Е	US-5,371,814	12-1994	Arnes et al.	385/25
	F	US-5,872,879	02-1999	Hamm, Mark A.	385/25
	G	US-6,263,133	07-2001	Hamm, Mark A.	385/33
	Н	US-			
,.	1	US-			
	J	US-			•
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.